

THE EMBODIMENTS OF THE INVENTION IN WHICH AN EXCLUSIVE PROPERTY OR PRIVILEGE IS CLAIMED ARE DEFINED AS FOLLOWS:

1. A non-contact tester for electronic circuits, comprising in combination:
an electronic circuit which includes at least one wireless i/o cell and means for sending and receiving signals via the at least one wireless i/o cell; and
an independent scanning head having at least one wireless i/o cell compatible with the at least one wireless i/o cell on the electronic circuit, such that data may be exchanged with the electronic circuit to confirm proper functioning of the electronic circuit.
2. The non-contact tester for electronic circuits as defined in claim 1, wherein a different circuit is provided for each of the at least one i/o cells to be tested.
3. The non-contact tester for electronic circuits as defined in claim 1, wherein the non-contact tester has a plurality of contact points which are adapted to correspond in a one to one relationship with a plurality of contact points provided on the electronic circuit being tested.
4. The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a radio frequency interface.
5. The non-contact tester for electronic circuits as defined in claim 4, wherein the radio frequency interface includes at least one transmitter and at least one receiver.
6. The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via the at least one wireless i/o cell is an optical interface.

7. The non-contact tester for electronic circuits as defined in claim 6, the optical interface includes at least one light emitter and at least one light receptor.
8. The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a magnetic interface.
9. The non-contact tester for electronic circuits as defined in claim 8, wherein the magnetic interface includes a magnetic detector and a magnetic generator.

10. A method of testing for electronic circuits, comprising the steps of:
 - providing a non-contact tester having an electronic circuit which includes at least one wireless i/o cell and means for sending and receiving signals via the at least one wireless i/o cell;
 - providing an independent scanning head having at least one wireless i/o cell compatible with the at least one wireless i/o cell on the electronic circuit, such that data may be exchanged with the electronic circuit to confirm proper functioning of the electronic circuit; and
 - testing the electronic circuit to confirm proper functioning of the electric circuit.
11. The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a radio frequency interface.
12. The method as defined in claim 11, wherein the radio frequency interface includes at least one transmitter and at least one receiver.
13. The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is an optical interface.
14. The method as defined in claim 13, the optical interface includes at least one light emitter and at least one light receptor.
15. The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a magnetic interface.
16. The method defined in claim 15, wherein the magnetic interface includes a magnetic detector and a magnetic generator.